## Notice of References Cited Application/Control No. 10/814,148 Examiner Jack I. Berman Applicant(s)/Patent Under Reexamination YEOM ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
	Α	US-4,775,789	10-1988	Albridge et al.	250/251	
	В	US-2002/0033446	03-2002	Ichimura et al.	250/251	
	С	US-				
	D	US-				
	Е	US-				
	F	US-				
	G	US-				
	Н	US-				
	ı	US-				
	J	US-				
	к	US-				
	L	US-				
	м	US-				

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*	[	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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